

2N5861

CASE 79-02, STYLE 1
TO-39 (TO-205AD)

SWITCHING TRANSISTOR

NPN SILICON

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CEO}	50	Vdc
Collector-Base Voltage	V_{CBO}	100	Vdc
Emitter-Base Voltage	V_{EBO}	6.0	Vdc
Collector Current — Continuous	I_C	2.0	Adc
Total Device Dissipation @ $T_A = 25^\circ\text{C}$ Derate above 25°C	P_D	1.0 6.0	Watt $\text{mW}/^\circ\text{C}$
Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C	P_D	5.0 28.6	Watts $\text{mW}/^\circ\text{C}$
Operating and Storage Junction Temperature Range	T_J, T_{stg}	-65 to +200	$^\circ\text{C}$

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted.)

Characteristic	Symbol	Min	Max	Unit
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OFF CHARACTERISTICS

Collector-Emitter Breakdown Voltage(1) ($I_C = 10 \text{ mAdc}, I_B = 0$)	$V_{(BR)CEO}$	50	—	Vdc
Collector-Base Breakdown Voltage ($I_C = 100 \mu\text{Adc}, I_E = 0$)	$V_{(BR)CBO}$	100	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 10 \mu\text{Adc}, I_C = 0$)	$V_{(BR)EBO}$	6.0	—	Vdc
Collector Cutoff Current ($V_{CE} = 50 \text{ Vdc}, V_{BE(\text{off})} = 2.0 \text{ Vdc}$) ($V_{CE} = 50 \text{ Vdc}, V_{BE(\text{off})} = 2.0 \text{ Vdc}, T_A = 75^\circ\text{C}$)	I_{CEX}	— —	0.3 10	μAdc
Collector Cutoff Current ($V_{CB} = 50 \text{ Vdc}, I_E = 0$) ($V_{CB} = 50 \text{ Vdc}, I_E = 0, T_A = +75^\circ\text{C}$)	I_{CBO}	— —	0.3 10	μAdc
Emitter Cutoff Current ($V_{BE} = 5.0 \text{ Vdc}, I_C = 0$)	I_{EBO}	—	0.1	μAdc

ON CHARACTERISTICS(1)

DC Current Gain ($I_C = 500 \text{ mAdc}, V_{CE} = 1.0 \text{ Vdc}$) ($I_C = 500 \text{ mAdc}, V_{CE} = 1.0 \text{ Vdc}, T_A = -55^\circ\text{C}$)	h_{FE}	25 10	100 —	—
Collector-Emitter Saturation Voltage ($I_C = 500 \text{ mAdc}, I_B = 50 \text{ mAdc}$)	$V_{CE(\text{sat})}$	—	0.5	Vdc
Base-Emitter Saturation Voltage ($I_C = 500 \text{ mAdc}, I_B = 50 \text{ mAdc}$)	$V_{BE(\text{sat})}$	0.8	1.1	Vdc

SMALL-SIGNAL CHARACTERISTICS

Current-Gain — Bandwidth Product ($I_C = 50 \text{ mAdc}, V_{CE} = 10 \text{ Vdc}, f = 100 \text{ MHz}$)	f_T	200	—	MHz
Collector-Base Capacitance ($V_{CB} = 10 \text{ Vdc}, I_E = 0, f = 100 \text{ kHz}$)	C_{cb}	—	7.0	pF
Emitter-Base Capacitance ($V_{BE} = 0.5 \text{ Vdc}, I_C = 0, f = 100 \text{ kHz}$)	C_{eb}	—	60	pF

SWITCHING CHARACTERISTICS

Turn-On Time	($V_{CC} = 30 \text{ Vdc}, V_{BE(\text{off})} = 2.0 \text{ Vdc},$ $I_C = 500 \text{ mAdc}, I_{B1} = 50 \text{ mAdc}$)	t_{on}	—	25	ns
Delay Time		t_d	—	8.0	ns
Rise Time		t_r	—	18	ns

ELECTRICAL CHARACTERISTICS (continued) ($T_A = 25^\circ\text{C}$ unless otherwise noted.)

Characteristic		Symbol	Min	Max	Unit
Turn-Off Time	$V_{CC} = 30\text{ Vdc}$, $I_C = 500\text{ mAdc}$, $I_{B1} = I_{B2} = 50\text{ mAdc}$	t_{off}	—	60	ns
Storage Time		t_s	—	35	ns
Fall Time		t_f	—	35	ns

(1) Pulse Test: Pulse Width $\leq 300\ \mu\text{s}$, Duty Cycle $\leq 2.0\%$

TYPICAL DYNAMIC CHARACTERISTICS

FIGURE 1 – CURRENT-GAIN-BANDWIDTH PRODUCT

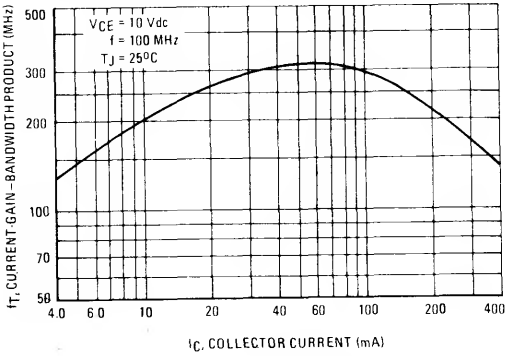


FIGURE 2 – CAPACITANCE

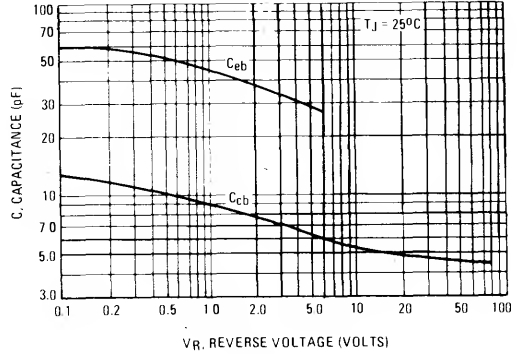


FIGURE 3 – TURN-ON TIME

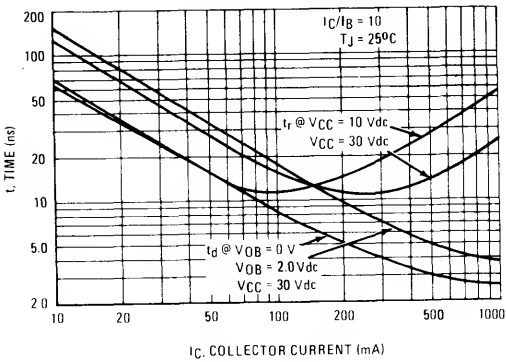


FIGURE 4 – TURN-OFF TIME

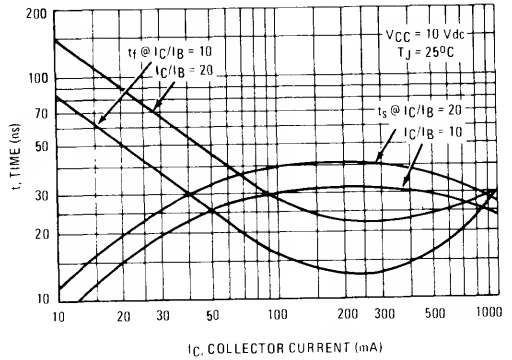
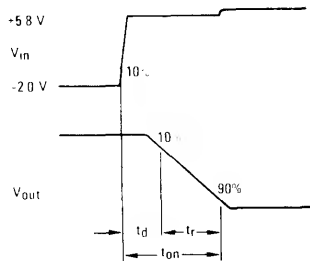
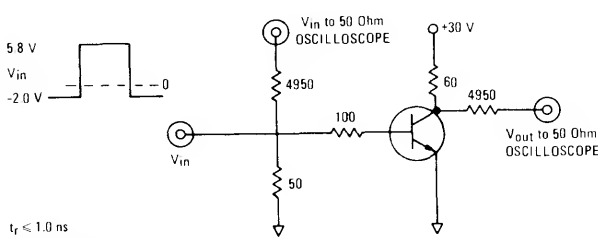


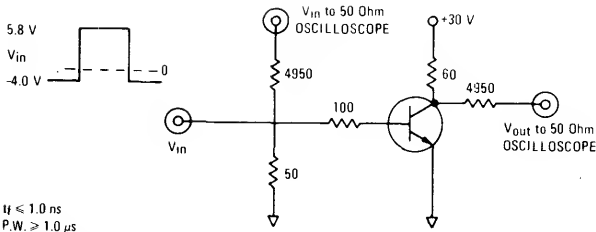
FIGURE 5 – TURN-ON TIME TEST CIRCUIT



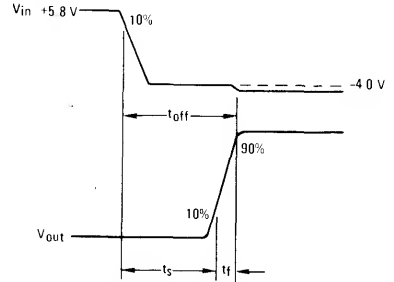
$t_r \leq 1.0\text{ ns}$
 $PW \geq 200\text{ ns}$
 Duty Cycle $\leq 2.0\%$
 Generator Source Impedance = $50\ \Omega$
 Pulse Generator: EH1421 Timing Unit and 1121 Pulse Driver
 Oscilloscope: Tektronix 661 Sampling Scope

V_{in} during t_{on} interval must be $+5.8\text{ V}$.
 All waveforms and bias levels must be set with unit in circuit

FIGURE 6 – TURN-OFF TIME TEST CIRCUIT



$t_f \leq 1.0$ ns
 P.W. ≥ 1.0 μ s
 Duty Cycle ≤ 2 0%
 Generator Source Impedance = 50 Ω
 Pulse Generator: EH1421 Timing Unit and 1121 Pulse Driver
 Oscilloscope: Tektronix 661 Sampling Scope



V_{in} during t_{off} interval must be -4.0 V.
 All waveforms and bias levels must be set with unit in circuit.

FIGURE 7 – DC CURRENT GAIN

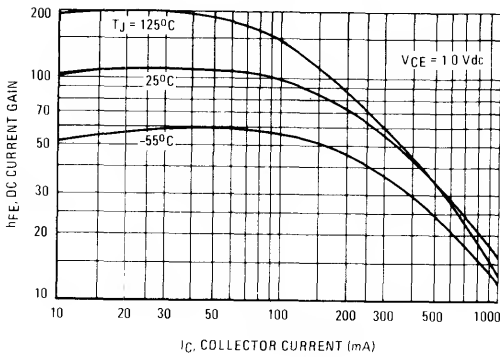


FIGURE 8 – "ON" VOLTAGES

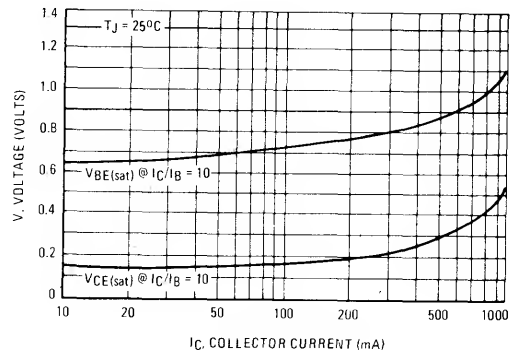
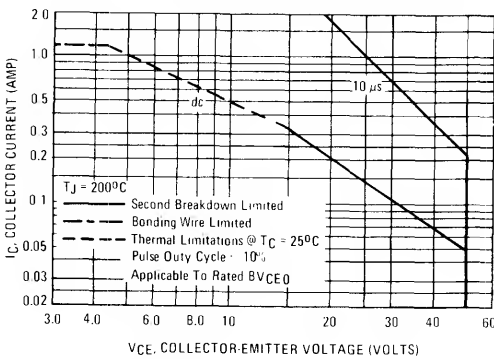


FIGURE 9 – ACTIVE-REGION SAFE OPERATING AREA



There are two limitations on the power handling ability of a transistor: junction temperature and secondary breakdown. Safe operating area curves indicate I_C - V_{CE} limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 9 is based on $T_{J(pk)} = 200^\circ\text{C}$; T_C is variable depending on conditions. Pulse curves are valid for duty cycles of 10% provided $T_{J(pk)} \leq 200^\circ\text{C}$. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by secondary breakdown.

FIGURE 10 – TEMPERATURE COEFFICIENTS

